

INTERNATIONAL SEARCH REPORT

International Application No PCT/IB2004/050985

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01N21/17 G01N21/63 G01N29/24

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 G01N

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, INSPEC

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 6 174 739 B1 (STEFFAN PAUL J) 16 January 2001 (2001-01-16) figures 4,5	1-16
X	LOGAN R ET AL: "MICROELECTRONIC FILM THICKNESS DETERMINATION USING A LASER-BASED ULTRASONIC TECHNIQUE" MATERIALS RESEARCH SOCIETY SYMPOSIUM PROCEEDINGS, MATERIALS RESEARCH SOCIETY, PITTSBURG, PA, US, vol. 440, 1997, pages 347-352, XP001019773 ISSN: 0272-9172 page 350; figures 3,4	1-16
X	US 6 256 100 B1 (ROGERS JOHN A ET AL) 3 July 2001 (2001-07-03) column 9; figures 7,8	1-16

Further documents are listed in the continuation of box C.

Patent family members are listed in annex.

* Special categories of cited documents :

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X document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

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& document member of the same patent family

Date of the actual completion of the International search	Date of mailing of the International search report
3 September 2004	21/09/2004
Name and mailing address of the ISA	Authorized officer

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	GOSTEIN M ET AL: "Non-contact metal film metrology using impulsive stimulated thermal scattering" CHARACTERIZATION AND METROLOGY FOR ULSI TECHNOLOGY 2000. INTERNATIONAL CONFERENCE 26-29 JUNE 2000 GAITHERSBURG, MD, USA, no. 550, pages 478-488, XP002294908 AIP Conference Proceedings 2001 AIP USA ISSN: 0094-243X figures 8,9,14 -----	1-16
X	MAZNEV A A ET AL: "Precise determination of thin metal film thickness with laser-induced acoustic grating technique" NONDESTRUCTIVE METHODS FOR MATERIALS CHARACTERIZATION. SYMPOSIUM 29-30 NOV. 1999 BOSTON, MA, USA, pages 195-200, XP009035956 Nondestructive Methods for Materials Characterization. Symposium (Materials Research Society Symposium Proceedings Vol. 591) 2000 Mater. Res. Soc Warrendale, PA, USA ISBN: 1-55899-499-8 figure 7 -----	1-16
X	BANET M ET AL: "All-optical, non-contact measurement of copper and tantalum films deposited by PVD and ECD in blanket films and single damascene structures" CHARACTERIZATION AND METROLOGY FOR ULSI TECHNOLOGY. 1998 INTERNATIONAL CONFERENCE 23-27 MARCH 1998 GAITHERSBURG, MD, USA, no. 449, pages 419-423, XP009035961 AIP Conference Proceedings 1998 AIP USA ISSN: 0094-243X page 422 -----	1-16
A	US 5 982 482 A (ROGERS JOHN A ET AL) 9 November 1999 (1999-11-09) figure 5A -----	1-16

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Information on patent family members

International Application No
PCT/IB2004/050985

Patent document cited in search report	Publication date	Patent family member(s)			Publication date
US 6174739	B1	16-01-2001	NONE		
US 6256100	B1	03-07-2001	EP 0991915 A1 WO 9956077 A1 JP 2002508081 T US 2003058449 A1		12-04-2000 04-11-1999 12-03-2002 27-03-2003
US 5982482	A	09-11-1999	NONE		